

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249646US2SDIV		SERIAL NO. 10/801,053 New-Divisional Application	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT					
		Yasufumi TSUMAGARI, et al.					
		FILING DATE		Herewith		GROUP	
						Unassigned 2616	

VFS

VMS

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
VFS	AA	6,253,026 B1	26Jun01	Saeki et al.			
VFS	AB	6,263,155 B1	17Jul01	Saeki et al.			
VFS	AC	6,188,835 B1	13Feb01	Grandbols			
VMS	AD	5,838,301	17Nov98	Okamoto et al.			
VMS	AE	6,078,727	20Jun00	Saeki et al.			
VMS	AF	6,360,057 B1	19Mar02	Tsumagari et al.			
VMS	AG	6,181,870	Jan 2001	Okada et al.			
VMS	AH	6,108,486	Aug 2000	Sawabe et al.			
VMS	AI	6,088,507	Jul 2000	Yamauchi et al.			
VMS	AJ	5,784,528	Jul 1998	Yamane et al.			
VMS	AK	5,771,334	Jun 1998	Yamauchi et al.			
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
VFS	AO	JP 9-245413	19Sep97	JAPAN	x	
VFS	AP	JP 11-96730	9Apr99	JAPAN (with English Abstract) (corresponding to U.S. Patent Nos. 6,253,026 B1 and 6,263,155 B1 (listed above))		x
VFS	AQ	JP 6-103317	15Apr94	JAPAN	x	
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

VFS	AW	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1999-131475 (with English translation)	
VMS	AX	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-284024 (with English translation)	
VMS	AY	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-284023 (with English translation)	
	AZ		<input type="checkbox"/> Additional References sheet(s) attached

Examiner *[Signature]*Date Considered *2/20/2006*

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.